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113 and L14
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L16	113 not L15	40	L16
L15	113 and L14	11	L15
L14	707/$.ccls.	23917	L14
L13	L12 and (object$ near3 table$)	51	L13
L12	L11 and updat$	279	L12
L11	L10 and link$	316	L11
L10	L8 and rat$	351	L10
L9	L8 and (object$ near3 table$)	85	L9
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L7	L6 and object$	564	L7
L6	L5 and (user or client)	713	L6
L5	L4 and (host or server)	978	L5
L4	L3 and (DAT or (data adj access adj system))	4768	L4
L3	carrier	1404078	L3
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L2   6163813.pn.   1   L2

L1   (4122532 or 4138735 or 4249241 or 4320461 or 4528644 or 4736687 or
4901237 or 4999806 or 5014193 or 5040132 or 5072397 or 5077660 or
5107455 or 5193180 or 5247683 or 5261080 or 5287270 or 5303379 or
5325290 or 5367671 or 5369401 or 5421009 or 5446896 or 5473630 or
5515425 or 5548756 or 5550976 or 5555416 or 5581463 or 5604906 or   57   L1
5612884 or 5666493 or 5666501 or 5729457 or 5748980 or 5752027 or
5758154 or 5758329 or 5771381 or 5778348 or 5787246 or 5809329 or
5812991 or 5835777 or 5845090 or 5852813 or 5860012 or 5881236 or
5909575 or 5909581 or 5933647 or 5956505 or 5963743 or 6012065 or
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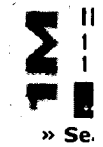
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